

**Search Notes**

Application/Control No.

10/767,725

Examiner

Thomas D. Lee

Applicant(s)/Patent under  
Reexamination

OGAWA, HIDEHIKO

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner
358	1.15, 402, 440	12/8/2005	TDL
379	100.01	12/8/2005	TDL
379	100.08	12/8/2005	TDL
379	100.13	12/8/2005	TDL
379	100.17	12/8/2005	TDL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR